

FNAL beam test results update

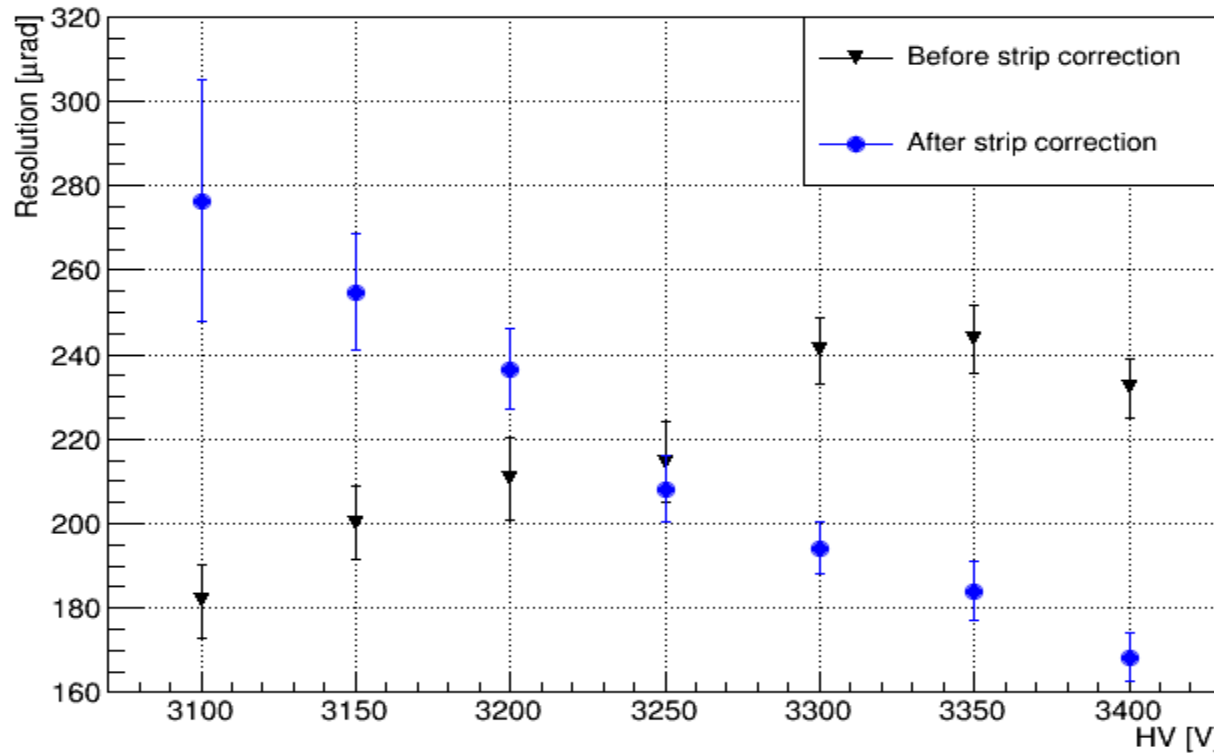
-- resolutions after strip nonlinear correction

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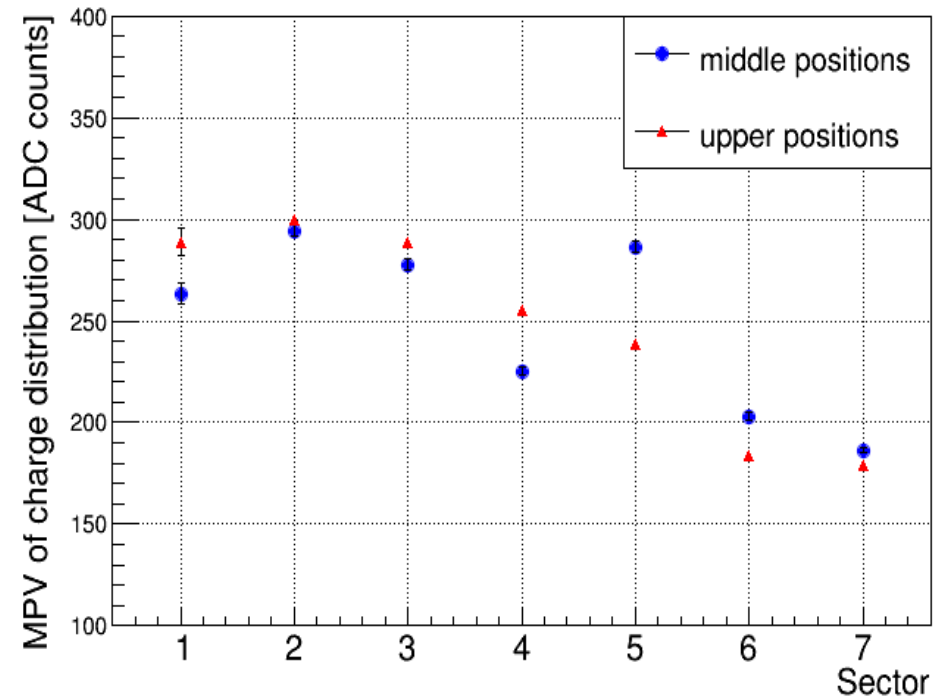
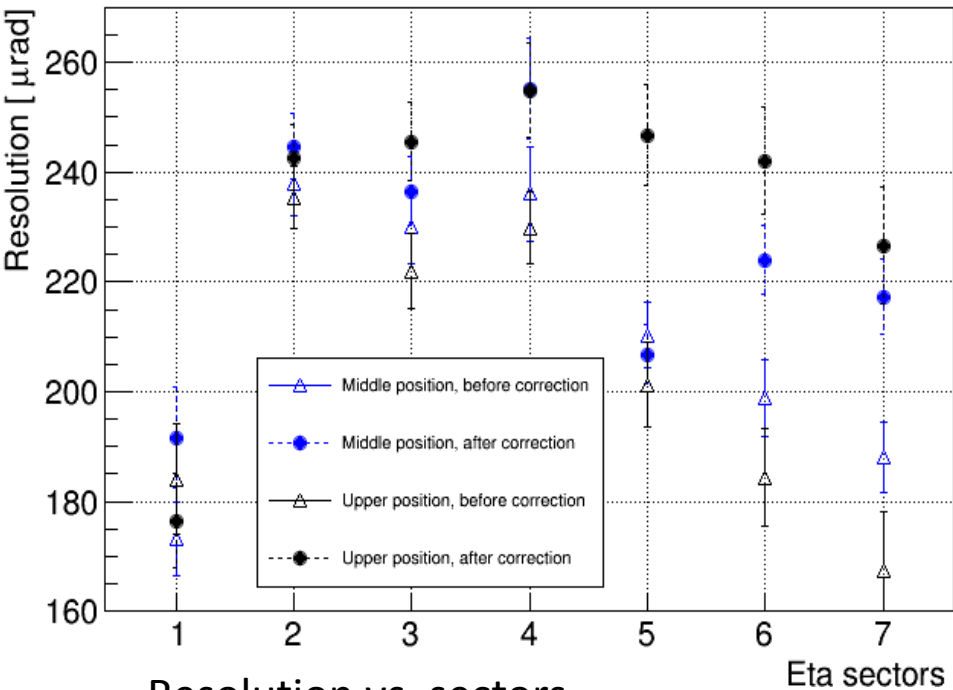
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HV scan on middle sector 5 (Zigzag GEM)



- Only **2,3 & 4-strip** events are selected and corrected (for both trackers and the zigzag detector).
- Detectors are aligned before and after correction respectively.
- Resolutions become worse at low voltages, while getting improved (by ~30%) at higher voltages.
- Results indicate strip non-linearity is gain dependent.

Position scan results at 3200V



“gain” vs. sectors